



CWT-E

Overall Card Warpage Test Tool

Application

This tool is designed to test the overall card warpage of the card after personalization for non-embossed cards (1,5mm) and embossed cards (2,5 mm).

It complies with ISO/IEC 7810 & 7811-1 norms.

It can be used for:

- Quality control / Production control.
- Support to CQM certification and audit.

Key Benefits

- Easy go/no-go quick control of the overall card warpage.
- Only one tool for both embossed and non-embossed cards by simply turning the gauge to the opposite side.



Access



Evolution



Productivity

Technical characteristics

Dimensions

W x D x H: 105 x 95 x 220 mm

Weight

1.2 kg

Mounting

can be easily grounded (against ESD)

Accessories

Gauge height 1.5mm
Gauge height 2.5mm

In compliance with E.C. directives

Associated products

Other MULANN products are nicely complementary:

- BWT-A or WTT-A control tools for bending stiffness and wrapping test
- TFD-A or TFD-P30 testers for dynamic bending
- PVT-A functional tester